

<b>Notice of References Cited</b>	Application/Control No. 10/727,764	Applicant(s)/Patent Under Reexamination WANG ET AL.	
	Examiner Stephen A. Holzen	Art Unit 3644	Page 1 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,787,579 A	11-1988	Smith, Peter	244/169
*	B	US-5,067,672 A	11-1991	Bouzat, Charles	244/158.5
*	C	US-5,139,218 A	08-1992	Bird et al.	244/165
*	D	US-5,349,532 A	09-1994	Tilley et al.	701/226
*	E	US-5,653,407 A	08-1997	Bertheux et al.	244/168
*	F	US-5,758,846 A	06-1998	Fowell, Richard A.	244/165
*	G	US-6,010,096 A	01-2000	Baghdasarian, Varouj	244/172.6
*	H	US-6,032,904 A	03-2000	Hosick et al.	244/169
*	I	US-2002/0020785 A1	02-2002	Eyerly, Bruce N.	244/164
*	J	US-6,470,270 B1	10-2002	Needelman et al.	701/222
*	K	US-2003/0057354 A1	03-2003	Wu et al.	250/203.1
*	L	US-6,681,159 B2	01-2004	Li et al.	701/13
*	M	US-6,691,033 B1	02-2004	Li et al.	701/222

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/727,764	Applicant(s)/Patent Under Reexamination WANG ET AL.	
	Examiner Stephen A. Holzen	Art Unit 3644	Page 2 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-4,617,634 A	10-1986	Izumida et al.	701/222
*	B	US-4,884,771 A	12-1989	Scheit et al.	244/165
*	C	US-5,149,022 A	09-1992	Flament, Patrick	244/168
*	D	US-5,562,266 A	10-1996	Achkar et al.	244/171
*	E	US-5,667,171 A	09-1997	Fowell et al.	244/165
*	F	US-5,745,869 A	04-1998	van Bezooijen, Roelof W.H.	701/222
*	G	US-6,266,616 B1	07-2001	Needelman, David D.	701/222
*	H	US-6,512,979 B1	01-2003	Needelman et al.	701/222
*	I	US-2003/0009284 A1	01-2003	Needelman et al.	701/222
*	J	US-2003/0093194 A1	05-2003	Li et al.	701/13
*	K	US-6,615,117 B2	09-2003	Li et al.	701/13
*	L	US-2003/0171855 A1	09-2003	Li et al.	701/4
*	M	US-2005/0071055 A1	03-2005	Needelman et al.	701/013

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

<b>Notice of References Cited</b>	Application/Control No. 10/727,764	Applicant(s)/Patent Under Reexamination WANG ET AL.	
	Examiner Stephen A. Holzen	Art Unit 3644	Page 3 of 3

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0117074 A1	06-2004	Wang et al.	701/013
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.